Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	Coldfire V2
Core Size	32-Bit Single-Core
Speed	66MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, QSPI, UART/USART, USB OTG
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	96
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 8x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/pcf52256cag66

Table of Contents

1 Family Configurations

Table 1. MCF52259 Family Configurations

Module	52252	52254	52255	52256	52258	52259
Version 2 ColdFire Core with eMAC (Enhanced multiply-accumulate unit) and CAU (Cryptographic acceleration unit)	•	•	•	•	•	•
System Clock	up to 66 or 80 MHz[1]		up to 80 MHz[1]	up to 66 or 80 MHz[1]		up to 80 MHz[1]
Performance (Dhrystone 2.1 MIPS)	up to 63 or 76					
Flash	256 KB	512 KB	512 KB	256 KB	512 KB	512 KB
Static RAM (SRAM)	32 KB	64 KB	64 KB	32 / 64 KB	64 KB	64 KB
Two Interrupt Controllers (INTC)	•	•	•	•	•	•
Fast Analog-to-Digital Converter (ADC)	•	•	•	•	•	•
USB On-The-Go (USB OTG)	•	•	•	•	•	•
Mini-FlexBus external bus interface	—	—	—	•	•	•
Fast Ethernet Controller (FEC)	•	•	•	•	•	•
Random Number Generator and Cryptographic Acceleration Unit (CAU)	—	—	•	—	—	•
FlexCAN 2.0B Module	Varies	Varies	•	Varies	Varies	•
Four-channel Direct-Memory Access (DMA)	•	•	•	•	•	•
Software Watchdog Timer (WDT)	•	•	•	•	•	•
Secondary Watchdog Timer	•	•	•	•	•	•
Two-channel Periodic Interrupt Timer (PIT)	2	2	2	2	2	2
Four-Channel General Purpose Timer (GPT)	•	•	•	•	•	•
32-bit DMA Timers	4	4	4	4	4	4
QSPI	•	•	•	•	•	•
UART(s)	3	3	3	3	3	3
I2C	2	2	2	2	2	2
Eight/Four-channel 8/16-bit PWM Timer	•	•	•	•	•	•
General Purpose I/O Module (GPIO)	•	•	•	•	•	•
Chip Configuration and Reset Controller Module	•	•	•	•	•	•
Background Debug Mode (BDM)	•	•	•	•	•	•
JTAG - IEEE 1149.1 Test Access Port	•	•	•	•	•	•
Package	100 LQFP			144 LQFP or 144 MAPBGA		

[1] 66 MHz = 63 MIPS; 80 MHz = 76 MIPS

  - Pre-divider capable of dividing the clock source frequency into the PLL reference frequency range
  - System can be clocked from PLL or directly from crystal oscillator or relaxation oscillator
  - Low power modes supported
  - 2^n ($0 \le n \le 15$) low-power divider for extremely low frequency operation
- Interrupt controller
  - Uniquely programmable vectors for all interrupt sources
  - Fully programmable level and priority for all peripheral interrupt sources
  - Seven external interrupt signals with fixed level and priority
  - Unique vector number for each interrupt source
  - Ability to mask any individual interrupt source or all interrupt sources (global mask-all)
  - Support for hardware and software interrupt acknowledge (IACK) cycles
  - Combinatorial path to provide wake-up from low-power modes
- DMA controller
  - Four fully programmable channels
  - Dual-address transfer support with 8-, 16-, and 32-bit data capability, along with support for 16-byte (4×32-bit) burst transfers
  - Source/destination address pointers that can increment or remain constant
  - 24-bit byte transfer counter per channel
  - Auto-alignment transfers supported for efficient block movement
  - Bursting and cycle-steal support
  - Software-programmable DMA requests for the UARTs (3) and 32-bit timers (4)
  - Channel linking support
- Reset
  - Separate reset in and reset out signals
  - Seven sources of reset:
    - Power-on reset (POR)
    - External
    - Software
    - Watchdog
    - Loss of clock / loss of lock
    - Low-voltage detection (LVD)
    - JTAG
  - Status flag indication of source of last reset
- Chip configuration module (CCM)
  - System configuration during reset
  - Selects one of six clock modes
  - Configures output pad drive strength
  - Unique part identification number and part revision number
- General purpose I/O interface
  - Up to 56 bits of general purpose I/O on 100-pin package
  - Up to 96 bits of general purpose I/O on 144-pin package
  - Bit manipulation supported via set/clear functions
  - Programmable drive strengths
  - Unused peripheral pins may be used as extra GPIO
- JTAG support for system level board testing

1.2.5 On-Chip Memories

1.2.5.1 SRAM

The dual-ported SRAM module provides a general-purpose 64 KB memory block that the ColdFire core can access in a single cycle. The location of the memory block can be set to any 64 KB boundary within the 4 GB address space. This memory is ideal for storing critical code or data structures and for use as the system stack. Because the SRAM module is physically connected to the processor's high-speed local bus, it can quickly service core-initiated accesses or memory-referencing commands from the debug module.

The SRAM module is also accessible by the DMA, FEC, and USB. The dual-ported nature of the SRAM makes it ideal for implementing applications with double-buffer schemes, where the processor and a DMA device operate in alternate regions of the SRAM to maximize system performance.

1.2.5.2 Flash Memory

The ColdFire flash module (CFM) is a non-volatile memory (NVM) module that connects to the processor’s high-speed local bus. The CFM is constructed with four banks of 64 KB×16-bit flash memory arrays to generate 512 KB of 32-bit flash memory. These electrically erasable and programmable arrays serve as non-volatile program and data memory. The flash memory is ideal for program and data storage for single-chip applications, allowing for field reprogramming without requiring an external high voltage source. The CFM interfaces to the ColdFire core through an optimized read-only memory controller that supports interleaved accesses from the 2-cycle flash memory arrays. A backdoor mapping of the flash memory is used for all program, erase, and verify operations, as well as providing a read datapath for the DMA. Flash memory may also be programmed via the EzPort, which is a serial flash memory programming interface that allows the flash memory to be read, erased and programmed by an external controller in a format compatible with most SPI bus flash memory chips.

1.2.6 Cryptographic Acceleration Unit

The MCF52235 device incorporates two hardware accelerators for cryptographic functions. First, the CAU is a coprocessor tightly-coupled to the V2 ColdFire core that implements a set of specialized operations to increase the throughput of software-based encryption and message digest functions, specifically the DES, 3DES, AES, MD5 and SHA-1 algorithms. Second, a random number generator provides FIPS-140 compliant 32-bit values to security processing routines. Both modules supply critical acceleration to software-based cryptographic algorithms at a minimal hardware cost.

1.2.7 Power Management

The device incorporates several low-power modes of operation entered under program control and exited by several external trigger events. An integrated power-on reset (POR) circuit monitors the input supply and forces an MCU reset as the supply voltage rises. The low voltage detector (LVD) monitors the supply voltage and is configurable to force a reset or interrupt condition if it falls below the LVD trip point. The RAM standby switch provides power to RAM when the supply voltage to the chip falls below the standby battery voltage.

1.2.8 FlexCAN

The FlexCAN module is a communication controller implementing version 2.0 of the CAN protocol parts A and B. The CAN protocol can be used as an industrial control serial data bus, meeting the specific requirements of reliable operation in a harsh EMI environment with high bandwidth. This instantiation of FlexCAN has 16 message buffers.

1.2.27 GPIO

Nearly all pins on the device have general purpose I/O capability and are grouped into 8-bit ports. Some ports do not use all eight bits. Each port has registers that configure, monitor, and control the port pin.

1.2.28 Part Numbers and Packaging

This product is RoHS-compliant. Refer to the product page at freescale.com or contact your sales office for up-to-date RoHS information.

Table 2. Orderable part number summary

Freescale Part Number	FlexCAN	Encryption	Speed (MHz)	Flash (KB)	SRAM (KB)	Package	Temp range (°C)
MCF52252AF80	—	—	80	256	32	100 LQFP	0 to +70
MCF52252CAF66	•	—	66				-40 to +85
MCF52254AF80	—	—	80	512	64	100 LQFP	0 to +70
MCF52254CAF66	•	—	66				-40 to +85
MCF52255CAF80	•	•	80	512	64	100 LQFP	-40 to +85
MCF52256AG80	—	—	80	256	32	144 LQFP	0 to +70
MCF52256CAG66	•	—	66		64		-40 to +85
MCF52256CVN66	•	—	66		64	144 MAPBGA	-40 to +85
MCF52256VN80	—	—	80		32		0 to +70
MCF52258AG80	—	—	80	512	64	144 LQFP	0 to +70
MCF52258CAG66	•	—	66				-40 to +85
MCF52258CVN66	•	—	66			144 MAPBGA	-40 to +85
MCF52258VN80	—	—	80				0 to +70
MCF52259CAG80	•	•	80	512	64	144 LQFP	-40 to +85
MCF52259CVN80	•	•				144 MAPBGA	-40 to +85

Figure 3 shows the pinout configuration for the 100 LQFP.

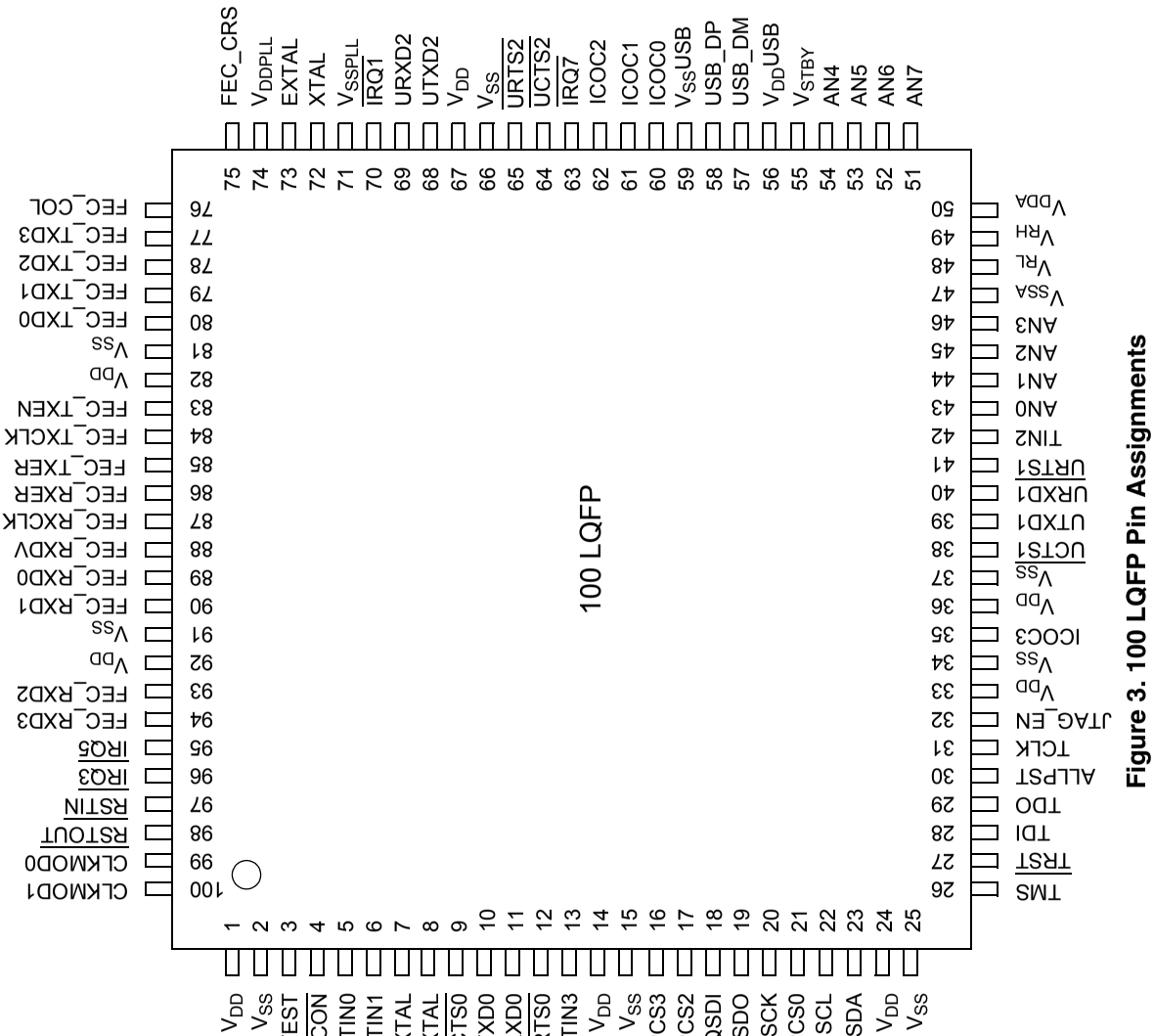

Figure 3. 100 LQFP Pin Assignments

Table 3 shows the pin functions by primary and alternate purpose, and illustrates which packages contain each pin.

Table 3. Pin Functions by Primary and Alternate Purpose

Pin Group	Primary Function	Secondary Function (Alt 1)	Tertiary Function (Alt 2)	Quaternary Function (GPIO)	Slew Rate	Drive Strength/Control[1]	Pull-up/ Pull-down[2]	Pin on 144 MAPBGA	Pin on 144 LQFP	Pin on 100 LQFP
ADC	AN[7:0]	—	—	PAN[7:0]	Low	Low	—	L12, K10, K12, K11, K9, L9, M10, M9	74–77; 69, 68, 67 ,66	51–54, 46, 45, 44, 43
	VDDA	—	—	—	N/A	N/A	—	L11	73	50
	VSSA	—	—	—	N/A	N/A	—	M12	70	47
	VRH	—	—	—	N/A	N/A	—	L10	72	49
	VRL	—	—	—	N/A	N/A	—	M11	71	48
Clock Generation	EXTAL	—	—	—	N/A	N/A	—	C12	106	73
	XTAL	—	—	—	N/A	N/A	—	D12	105	72
	VDDPLL	—	—	—	N/A	N/A	—	C11	107	74
	VSSPLL	—	—	—	N/A	N/A	—	D11	104	71
RTC	RTC_EXTAL	—	—	—	N/A	N/A	—	D1	13	7
	RTC_XTAL	—	—	—	N/A	N/A	—	E1	14	8
Debug Data	ALLPST	—	—	—	Low	High	—	L3	42	30
	DDATA[3:0]	—	—	PDD[7:4]	Low	High	—	G9, H10, F11, F10	86, 85, 84, 83	—
	PST[3:0]	—	—	PDD[3:0]	Low	High	—	F9, G10, G11, G12	87–90	—

Table 3. Pin Functions by Primary and Alternate Purpose (continued)

Pin Group	Primary Function	Secondary Function (Alt 1)	Tertiary Function (Alt 2)	Quaternary Function (GPIO)	Slew Rate	Drive Strength/Control[1]	Pull-up/ Pull-down[2]	Pin on 144 MAPBGA	Pin on 144 LQFP	Pin on 100 LQFP
FEC	FEC_COL	—	—	PTI0	PSRRH[0]	PDSRH[0]	—	B11	109	76
	FEC_CRS	—	—	PTI1	PSRRH[1]	PDSRH[1]	—	B12	108	75
	FEC_RXCLK	—	—	PTI2	PSRRH[2]	PDSRH[2]	—	B8	120	87
	FEC_RXD[3:0]	—	—	PTI[6:3]	PSRRH[6:3]	PDSRH[6:3]	—	D7, C7, B7, A8	127, 126, 123, 122	94, 93, 90, 89
	FEC_RXDV	—	—	PTI7	PSRRH[7]	PDSRH[7]	—	C8	121	88
	FEC_RXER	—	—	PTJ0	PSRRH[8]	PDSRH[8]	—	A9	119	86
	FEC_TXCLK	—	—	PTJ1	PSRRH[9]	PDSRH[9]	—	B9	117	84
	FEC_TXD[3:0]	—	—	PTJ[5:2]	PSRRH[13:10]	PDSRH[13:10]	—	A11, B10, C9, D9	110–113	77, 78, 79, 80
FEC	FEC_TXEN	—	—	PTJ6	PSRRH[14]	PDSRH[14]	—	A10	116	83
	FEC_TXER	—	—	PTJ7	PSRRH[15]	PDSRH[15]	—	D8	118	85
I2C0[3]	I2C_SCL0	—	UTXD2	PAS0	PSRR[0]	PDSR[0]	Pull-Up[4]	H1	28	22
	I2C_SDA0	—	URXD2	PAS1	PSRR[0]	PDSR[0]	Pull-Up[4]	H2	29	23
Interrupts	IRQ7	—	—	PNQ7	Low	Low	Pull-Up[4]	E12	96	63
	IRQ5	FEC_MDC	—	PNQ5	Low	Low	Pull-Up[4]	A7	128	95
	IRQ3	FEC_MDIO	—	PNQ3	Low	Low	Pull-Up[4]	A6	129	96
	IRQ1	—	USB_ALTCLK	PNQ1	Low	High	Pull-Up[4]	E9	103	70
JTAG/BDM	JTAG_EN	—	—	—	N/A	N/A	Pull-Down	M2	44	32
	TCLK/ PSTCLK/ CLKOUT	—	FB_CLK	—	Low	Low	Pull-Up[5]	M3	43	31
	TDI/DSI	—	—	—	N/A	N/A	Pull-Up[5]	L1	40	28
	TDO/DSO	—	—	—	Low	Low	—	L2	41	29
	TMS/$\overline{\text{BKPT}}$	—	—	—	N/A	N/A	Pull-Up[5]	K1	38	26
	$\overline{\text{TRST}}$/DSCLK	—	—	—	N/A	N/A	Pull-Up[5]	K2	39	27

Table 3. Pin Functions by Primary and Alternate Purpose (continued)

Pin Group	Primary Function	Secondary Function (Alt 1)	Tertiary Function (Alt 2)	Quaternary Function (GPIO)	Slew Rate	Drive Strength/Control[1]	Pull-up/ Pull-down[2]	Pin on 144 MAPBGA	Pin on 144 LQFP	Pin on 100 LQFP
Timer 1, 32-bit	DTIN1	DTOUT1	PWM2	PTC1	PSRR[17]	PDSR[17]	—	C1	12	6
Timer 0, 32-bit	DTIN0	DTOUT0	PWM0	PTC0	PSRR[16]	PDSR[16]	—	D2	11	5
UART 0	UCTS0	—	USB_VBUSE	PUA3	PSRR[11]	PDSR[11]	—	E2	15	9
	URTS0	—	USB_VBUSD	PUA2	PSRR[10]	PDSR[10]	—	F3	18	12
	URXD0	—	—	PUA1	PSRR[9]	PDSR[9]	—	F2	17	11
	UTXD0	—	—	PUA0	PSRR[8]	PDSR[8]	—	F1	16	10
UART 1	UCTS1	SYNCA	URXD2	PUB3	PSRR[15]	PDSR[15]	—	K7	61	38
	URTS1	SYNCB	UTXD2	PUB2	PSRR[14]	PDSR[14]	—	M8	64	41
	URXD1	I2C_SDA1	—	PUB1	PSRR[13]	PDSR[13]	Pull-Up[6]	L8	63	40
	UTXD1	I2C_SCL1	—	PUB0	PSRR[12]	PDSR[12]	Pull-Up[6]	K8	62	39
UART 2	UCTS2	I2C_SCL1	USB_VBUSCHG	PUC3	PSRR[27]	PDSR[27]	Pull-Up[6]	E11	97	64
	URTS2	I2C_SDA1	USB_VBUSDIS	PUC2	PSRR[26]	PDSR[26]	Pull-Up[6]	E10	98	65
	URXD2	CANRX	—	PUC1	PSRR[25]	PDSR[25]	—	C10	102	69
	UTXD2	CANTX	—	PUC0	PSRR[24]	PDSR[24]	—	D10	101	68
USB OTG	USB_DM	—	—	—	N/A	N/A	—	H11	80	57
	USB_DP	—	—	—	N/A	N/A	—	H12	81	58
	USB_VDD	—	—	—	N/A	N/A	—	J9	79	56
	USB_VSS	—	—	—	N/A	N/A	—	H9	82	59

2.2 Current Consumption

Table 5. Typical Active Current Consumption Specifications

Characteristic	Symbol	Typical[1] Active (SRAM)	Typical[1] Active (Flash)	Peak[2] (Flash)	Unit
PLL @ 8 MHz	I_{DD}	22	30	36	mA
PLL @ 16 MHz		31	45	60	
PLL @ 64 MHz		84	100	155	
PLL @ 80 MHz		102	118	185	
RAM standby supply current • Normal operation: $V_{DD} > V_{STBY}$ - 0.3 V • Standby operation: $V_{DD} < V_{SS}$ + 0.5 V	I_{STBY}	— —		5 20	μA μA
Analog supply current • Normal operation	I_{DDA}	2 [3]		15	mA
USB supply current	I_{DDUSB}	—		2	mA
PLL supply current	I_{DDPLL}	—		6 [4]	mA

1 Tested at room temperature with CPU polling a status register. All clocks were off except the UART and CFM (when running from flash memory).

2 Peak current measured with all modules active, CPU polling a status register, and default drive strength with matching load.

3 Tested using Auto Power Down (APD), which powers down the ADC between conversions; ADC running at 4 MHz in Once Parallel mode with a sample rate of 3 kHz.

4 Tested with the PLL MFD set to 7 (max value). Setting the MFD to a lower value results in lower current consumption.

Table 6. Current Consumption in Low-Power Mode, Code From Flash Memory[1,2,3]

Mode	8 MHz (Typ)	16 MHz (Typ)	64 MHz (Typ)	80 MHz (Typ)	Unit	Symbol
Stop mode 3 (Stop 11)[4]	0.150				mA	I_{DD}
Stop mode 2 (Stop 10)[4]	7.0					
Stop mode 1 (Stop 01)[4,5]	9	10	15	17		
Stop mode 0 (Stop 00)[5]	9	10	15	17		
Wait / Doze	21	32	56	65		
Run	23	36	70	81		

1 All values are measured with a 3.30 V power supply. Tests performed at room temperature.

2 Refer to the Power Management chapter in the *MCF52259 Reference Manual* for more information on low-power modes.

3 CLKOUT, PST/DDATA signals, and all peripheral clocks except UART0 and CFM off before entering low-power mode. CLKOUT is disabled.

4 See the description of the Low-Power Control Register (LPCR) in the *MCF52259 Reference Manual* for more information on stop modes 0–3.

5 Results are identical to STOP 00 for typical values because they only differ by CLKOUT power consumption. CLKOUT is already disabled in this instance prior to entering low-power mode.

Table 7. Current Consumption in Low-Power Mode, Code From SRAM[1,2,3]

Mode	8 MHz (Typ)	16 MHz (Typ)	64 MHz (Typ)	80 MHz (Typ)	Unit	Symbol
Stop mode 3 (Stop 11)[4]	0.090				mA	I_{DD}
Stop mode 2 (Stop 10)[4]	7					
Stop mode 1 (Stop 01)[4,5]	9	10	15	17		
Stop mode 0 (Stop 00)[5]	9	10	15	17		
Wait / Doze	13	18	42	50		
Run	16	21	55	65		

1 All values are measured with a 3.3 V power supply. Tests performed at room temperature.
2 Refer to the Power Management chapter in the *MCF52259 Reference Manual* for more information on low-power modes.
3 CLKOUT, PST/DDATA signals, and all peripheral clocks except UART0 off before entering low-power mode. CLKOUT is disabled. Code executed from SRAM with flash memory shut off by writing 0x0 to the FLASHBAR register.
4 See the description of the Low-Power Control Register (LPCR) in the *MCF52259 Reference Manual* for more information on stop modes 0–3.
5 Results are identical to STOP 00 for typical values because they only differ by CLKOUT power consumption. CLKOUT is already disabled in this instance prior to entering low-power mode.

2.3 Thermal Characteristics

Table 8 lists thermal resistance values.

Table 8. Thermal Characteristics

	Characteristic		Symbol	Value	Unit
144 MAPBGA	Junction to ambient, natural convection	Single layer board (1s)	θ_{JA}	53[1,2]	°C/W
	Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JA}	30[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Single layer board (1s)	θ_{JMA}	43[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	26[1,3]	°C/W
	Junction to board	—	θ_{JB}	16[4]	°C/W
	Junction to case	—	θ_{JC}	9[5]	°C/W
	Junction to top of package	Natural convection	Ψ_{jt}	2[6]	°C/W
	Maximum operating junction temperature	—	T_j	105	°C
144 LQFP	Junction to ambient, natural convection	Single layer board (1s)	θ_{JA}	44[7,8]	°C/W
	Junction to ambient, natural convection	Four layer board (2s2p)	θ_{JA}	35[1,9]	°C/W
	Junction to ambient, (@200 ft/min)	Single layer board (1s)	θ_{JMA}	35[1,3]	°C/W
	Junction to ambient, (@200 ft/min)	Four layer board (2s2p)	θ_{JMA}	29[1,3]	°C/W
	Junction to board	—	θ_{JB}	23[10]	°C/W
	Junction to case	—	θ_{JC}	7[11]	°C/W
	Junction to top of package	Natural convection	Ψ_{jt}	2[12]	°C/W
	Maximum operating junction temperature	—	T_j	105	°C

[16] Thermal resistance between the die and the printed circuit board in conformance with JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

[17] Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1).

[18] Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written in conformance with Psi-JT.

The average chip-junction temperature (T_J) in °C can be obtained from:

$$T_J = T_A + (P_D \times \Theta_{JMA}) \quad (1)$$

Where:

T_A = ambient temperature, °C

Θ_{JA} = package thermal resistance, junction-to-ambient, °C/W

P_D = $P_{INT} + P_{I/O}$

P_{INT} = chip internal power, $I_{DD} \times V_{DD}$, W

$P_{I/O}$ = power dissipation on input and output pins — user determined, W

For most applications $P_{I/O} < P_{INT}$ and can be ignored. An approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected) is:

$$P_D = K \div (T_J + 273°C) \quad (2)$$

Solving equations 1 and 2 for K gives:

$$K = P_D \times (T_A + 273\ °C) + \Theta_{JMA} \times P_D^2 \quad (3)$$

where K is a constant pertaining to the particular part. K can be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A. Using this value of K, the values of P_D and T_J can be obtained by solving equations (1) and (2) iteratively for any value of T_A.

2.4 Flash Memory Characteristics

The flash memory characteristics are shown in Table 9 and Table 10.

Table 9. SGFM Flash Program and Erase Characteristics

(V_{DD} = 3.0 to 3.6 V)

Parameter	Symbol	Min	Typ	Max	Unit
System clock (read only)	$f_{sys(R)}$	0	—	66.67 or 80[1]	MHz
System clock (program/erase)[2]	$f_{sys(P/E)}$	0.15	—	66.67 or 80[1]	MHz

1 Depending on packaging; see the orderable part number summary (Table 2).

2 Refer to the flash memory section for more information (Section 2.4, “Flash Memory Characteristics”)

Table 10. SGFM Flash Module Life Characteristics

(V_{DD} = 3.0 to 3.6 V)

Parameter	Symbol	Value	Unit
Maximum number of guaranteed program/erase cycles[1] before failure	P/E	10,000[2]	Cycles
Data retention at average operating temperature of 85°C	Retention	10	Years

1 A program/erase cycle is defined as switching the bits from 1 → 0 → 1.

2.7 DC Electrical Specifications

Table 13. DC Electrical Specifications [1]

Characteristic	Symbol	Min	Max	Unit
Supply voltage	V_{DD}	3.0	3.6	V
Standby voltage	V_{STBY}	1.8	3.5	V
Input high voltage	V_{IH}	$0.7 \times V_{DD}$	4.0	V
Input low voltage	V_{IL}	$V_{SS} - 0.3$	$0.35 \times V_{DD}$	V
Input hysteresis[2]	V_{HYS}	$0.06 \times V_{DD}$	—	mV
Low-voltage detect trip voltage (V_{DD} falling)	V_{LVD}	2.15	2.3	V
Low-voltage detect hysteresis (V_{DD} rising)	V_{LVDHYS}	60	120	mV
Input leakage current $V_{in} = V_{DD}$ or V_{SS}, digital pins	I_{in}	–1.0	1.0	μA
Output high voltage (all input/output and all output pins) I_{OH} = –2.0 mA	V_{OH}	$V_{DD} - 0.5$	—	V
Output low voltage (all input/output and all output pins) I_{OL} = 2.0 mA	V_{OL}	—	0.5	V
Output high voltage (high drive) I_{OH} = -5 mA	V_{OH}	$V_{DD} - 0.5$	—	V
Output low voltage (high drive) I_{OL} = 5 mA	V_{OL}	—	0.5	V
Output high voltage (low drive) I_{OH} = -2 mA	V_{OH}	V_{DD} - 0.5	—	V
Output low voltage (low drive) I_{OL} = 2 mA	V_{OL}	—	0.5	V
Weak internal pull Up device current, tested at V_{IL} Max.[3]	I_{APU}	–10	–130	μA
Input Capacitance [4] • All input-only pins • All input/output (three-state) pins	C_{in}	 — —	 7 7	pF

1 Refer to Table 14 for additional PLL specifications.

2 Only for pins: IRQ1, IRQ3. IRQ5, IRQ7, RSTIN_B, TEST, RCON_B, PCS0, SCK, I2C_SDA, I2C_SCL, TCLK, TRST_B

3 Refer to Table 3 for pins having internal pull-up devices.

4 This parameter is characterized before qualification rather than 100% tested.

2.8 Clock Source Electrical Specifications

Table 14. Oscillator and PLL Specifications

(V_{DD} and V_{DDPLL} = 3.0 to 3.6 V, V_{SS} = V_{SSPLL} = 0 V)

Characteristic	Symbol	Min	Max	Unit
Clock Source Frequency Range of EXTAL Frequency Range • Crystal • External[1]	 $f_{crystal}$ f_{ext}	 12 0	 25.0[2] 66.67 or 80	MHz
PLL reference frequency range	f_{ref_pll}	2	10.0	MHz
System frequency [3] • External clock mode • On-chip PLL frequency	f_{sys}	 0 f_{ref} / 32	 66.67 or 80[4] 66.67 or 80[4]	MHz
Loss of reference frequency [5, 7]	f_{LOR}	100	1000	kHz
Self clocked mode frequency [6]	f_{SCM}	1	5	MHz
Crystal start-up time [7, 8]	t_{cst}	—	0.1	ms
EXTAL input high voltage • External reference	V_{IHEXT}	 2.0	 3.0[2]	V
EXTAL input low voltage • External reference	V_{ILEXT}	 V_{SS}	 0.8	V
PLL lock time[4,9]	t_{lpll}	—	500	µs
Duty cycle of reference [4]	t_{dc}	40	60	% f_{ref}
Frequency un-LOCK range	f_{UL}	–1.5	1.5	% f_{ref}
Frequency LOCK range	f_{LCK}	–0.75	0.75	% f_{ref}
CLKOUT period jitter [4, 5, 10 ,11], measured at f_{SYS} Max • Peak-to-peak (clock edge to clock edge) • Long term (averaged over 2 ms interval)	C_{jitter}	 — —	 10 .01	% f_{sys}
On-chip oscillator frequency	f_{oco}	7.84	8.16	MHz

1 In external clock mode, it is possible to run the chip directly from an external clock source without enabling the PLL.

2 This value has been updated.

3 All internal registers retain data at 0 Hz.

4 Depending on packaging; see the orderable part number summary (Table 2).

5 Loss of Reference Frequency is the reference frequency detected internally, which transitions the PLL into self clocked mode.

6 Self clocked mode frequency is the frequency at which the PLL operates when the reference frequency falls below f_{LOR} with default MFD/RFD settings.

7 This parameter is characterized before qualification rather than 100% tested.

8 Proper PC board layout procedures must be followed to achieve specifications.

9 This specification applies to the period required for the PLL to relock after changing the MFD frequency control bits in the synthesizer control register (SYNCR).

10 Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum f_{sys}. Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the PLL circuitry via V_{DDPLL} and V_{SSPLL} and variation in crystal oscillator frequency increase the C_{jitter} percentage for a given interval.

11 Based on slow system clock of 40 MHz measured at f_{sys} max.

- 25 pF / 25 Ω for low drive

Table 21. GPIO Timing

NUM	Characteristic	Symbol	Min	Max	Unit
G1	CLKOUT High to GPIO Output Valid	t_{CHPOV}	—	10	ns
G2	CLKOUT High to GPIO Output Invalid	t_{CHPOI}	1.5	—	ns
G3	GPIO Input Valid to CLKOUT High	t_{PVCH}	9	—	ns
G4	CLKOUT High to GPIO Input Invalid	t_{CHPI}	1.5	—	ns

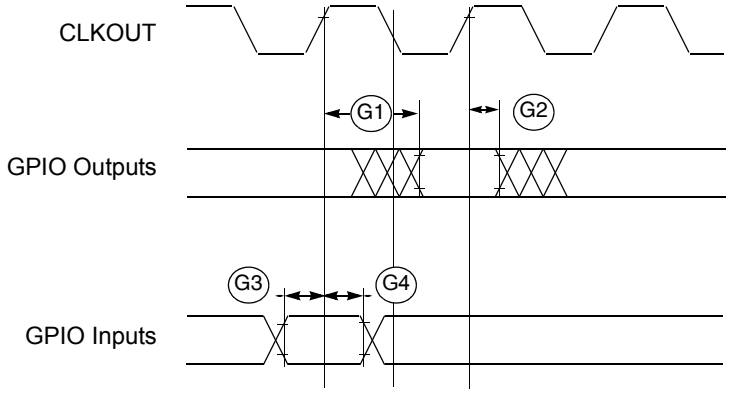

Figure 11. GPIO Timing

2.13 Reset Timing

Table 22. Reset and Configuration Override Timing

(V_{DD} = 3.0 to 3.6 V, V_{SS} = 0 V, $T_A = T_L$ to T_H)[1]

NUM	Characteristic	Symbol	Min	Max	Unit
R1	$\overline{RSTI}$ input valid to CLKOUT High	t_{RVCH}	9	—	ns
R2	CLKOUT High to $\overline{RSTI}$ Input invalid	t_{CHRI}	1.5	—	ns
R3	$\overline{RSTI}$ input valid time [2]	t_{RIVT}	5	—	t_{CYC}
R4	CLKOUT High to $\overline{RSTO}$ Valid	t_{CHROV}	—	10	ns

[1] All AC timing is shown with respect to 50% V_{DD} levels unless otherwise noted.

[2] During low power STOP, the synchronizers for the $\overline{RSTI}$ input are bypassed and $\overline{RSTI}$ is asserted asynchronously to the system. Thus, $\overline{RSTI}$ must be held a minimum of 100 ns.

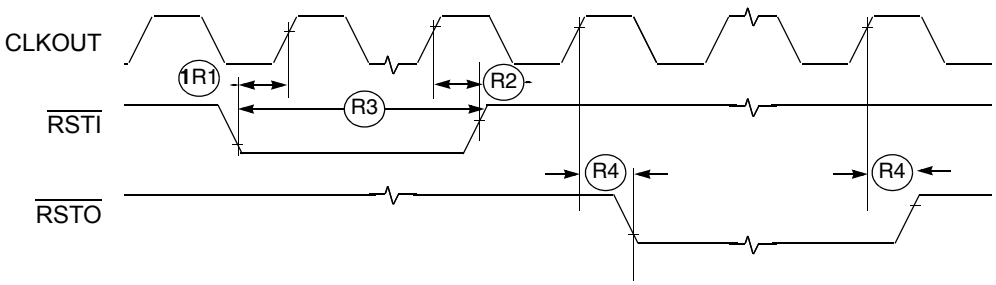

Figure 12. $\overline{RSTI}$ and Configuration Override Timing

2.14 I2C Input/Output Timing Specifications

Table 23 lists specifications for the I2C input timing parameters shown in Figure 13.

Table 23. I2C Input Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1	Start condition hold time	$2 \times t_{CYC}$	—	ns
I2	Clock low period	$8 \times t_{CYC}$	—	ns
I3	SCL/SDA rise time (V_{IL} = 0.5 V to V_{IH} = 2.4 V)	—	1	ms
I4	Data hold time	0	—	ns
I5	SCL/SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V)	—	1	ms
I6	Clock high time	$4 \times t_{CYC}$	—	ns
I7	Data setup time	0	—	ns
I8	Start condition setup time (for repeated start condition only)	$2 \times t_{CYC}$	—	ns
I9	Stop condition setup time	$2 \times t_{CYC}$	—	ns

Table 24 lists specifications for the I2C output timing parameters shown in Figure 13.

Table 24. I2C Output Timing Specifications between I2C_SCL and I2C_SDA

Num	Characteristic	Min	Max	Units
I1[1]	Start condition hold time	$6 \times t_{CYC}$	—	ns
I2[1]	Clock low period	$10 \times t_{CYC}$	—	ns
I3[2]	I2C_SCL/I2C_SDA rise time (V_{IL} = 0.5 V to V_{IH} = 2.4 V)	—	—	µs
I4[1]	Data hold time	$7 \times t_{CYC}$	—	ns
I5[3]	I2C_SCL/I2C_SDA fall time (V_{IH} = 2.4 V to V_{IL} = 0.5 V)	—	3	ns
I6[1]	Clock high time	$10 \times t_{CYC}$	—	ns
I7[1]	Data setup time	$2 \times t_{CYC}$	—	ns
I8[1]	Start condition setup time (for repeated start condition only)	$20 \times t_{CYC}$	—	ns
I9[1]	Stop condition setup time	$10 \times t_{CYC}$	—	ns

1 Output numbers depend on the value programmed into the IFDR; an IFDR programmed with the maximum frequency (IFDR = 0x20) results in minimum output timings as shown in Table 24. The I^2C interface is designed to scale the actual data transition time to move it to the middle of the SCL low period. The actual position is affected by the prescale and division values programmed into the IFDR; however, the numbers given in Table 24 are minimum values.

2 Because SCL and SDA are open-collector-type outputs, which the processor can only actively drive low, the time SCL or SDA take to reach a high level depends on external signal capacitance and pull-up resistor values.

3 Specified at a nominal 50 pF load.

2.17 DMA Timers Timing Specifications

Table 26 lists timer module AC timings.

Table 26. Timer Module AC Timing Specifications

Name	Characteristic[1]	Min	Max	Unit
T1	DTIN0 / DTIN1 / DTIN2 / DTIN3 cycle time	$3 \times t_{CYC}$	—	ns
T2	DTIN0 / DTIN1 / DTIN2 / DTIN3 pulse width	$1 \times t_{CYC}$	—	ns

1 All timing references to CLKOUT are given to its rising edge.

2.18 QSPI Electrical Specifications

Table 27 lists QSPI timings.

Table 27. QSPI Modules AC Timing Specifications

Name	Characteristic	Min	Max	Unit
QS1	QSPI_CS[3:0] to QSPI_CLK	1	510	t_{CYC}
QS2	QSPI_CLK high to QSPI_DOUT valid	—	10	ns
QS3	QSPI_CLK high to QSPI_DOUT invalid (Output hold)	2	—	ns
QS4	QSPI_DIN to QSPI_CLK (Input setup)	9	—	ns
QS5	QSPI_DIN to QSPI_CLK (Input hold)	9	—	ns

The values in Table 27 correspond to Figure 15.

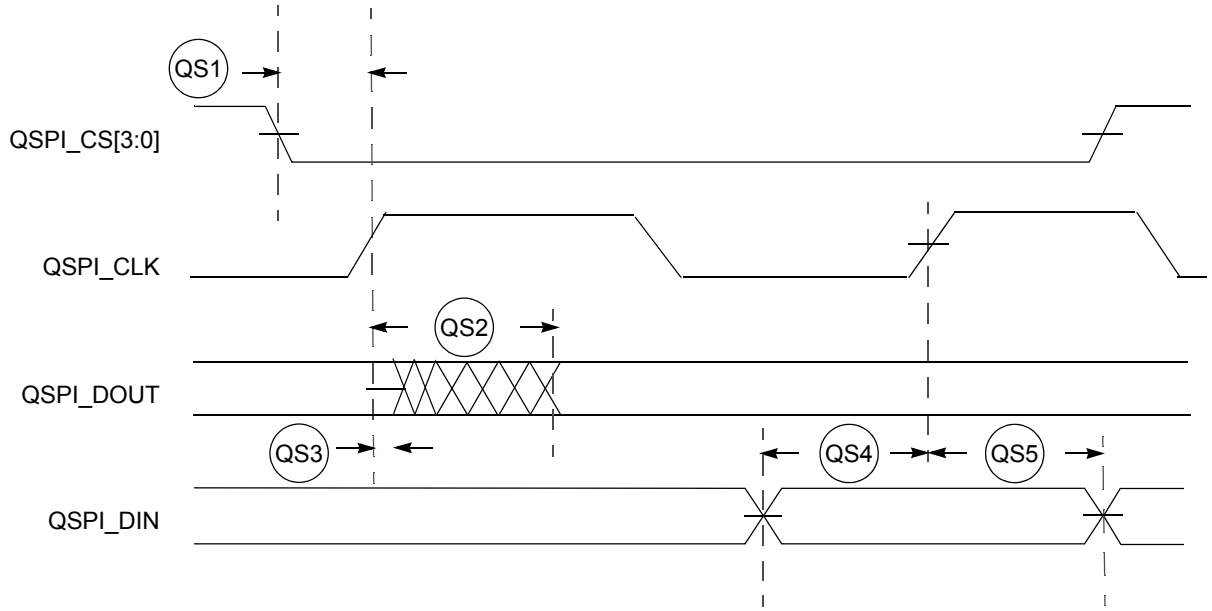

Figure 15. QSPI Timing

2.19 JTAG and Boundary Scan Timing

Table 28. JTAG and Boundary Scan Timing

Num	Characteristics[1]	Symbol	Min	Max	Unit
J1	TCLK frequency of operation	f_{JCYC}	DC	1/4	$f_{sys/2}$
J2	TCLK cycle period	t_{JCYC}	$4 \times t_{CYC}$	—	ns
J3	TCLK clock pulse width	t_{JCW}	26	—	ns
J4	TCLK rise and fall times	t_{JCRF}	0	3	ns
J5	Boundary scan input data setup time to TCLK rise	t_{BSDST}	4	—	ns
J6	Boundary scan input data hold time after TCLK rise	t_{BSDHT}	26	—	ns
J7	TCLK low to boundary scan output data valid	t_{BSDV}	0	33	ns
J8	TCLK low to boundary scan output high Z	t_{BSDZ}	0	33	ns
J9	TMS, TDI input data setup time to TCLK rise	t_{TAPBST}	4	—	ns
J10	TMS, TDI Input data hold time after TCLK rise	t_{TAPBHT}	10	—	ns
J11	TCLK low to TDO data valid	t_{TDODV}	0	26	ns
J12	TCLK low to TDO high Z	t_{TDODZ}	0	8	ns
J13	$\overline{\text{TRST}}$ assert time	t_{TRSTAT}	100	—	ns
J14	$\overline{\text{TRST}}$ setup time (negation) to TCLK high	t_{TRSTST}	10	—	ns

[1] JTAG_EN is expected to be a static signal. Hence, it is not associated with any timing.

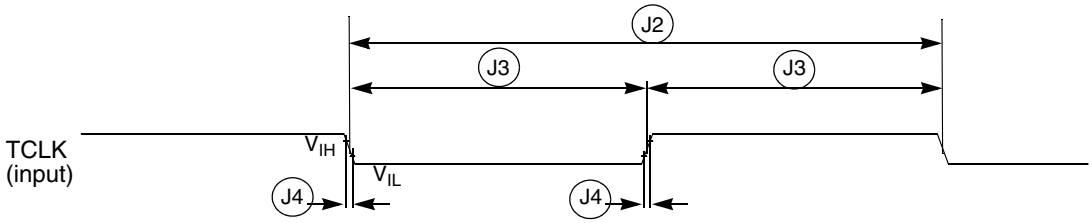

Figure 16. Test Clock Input Timing

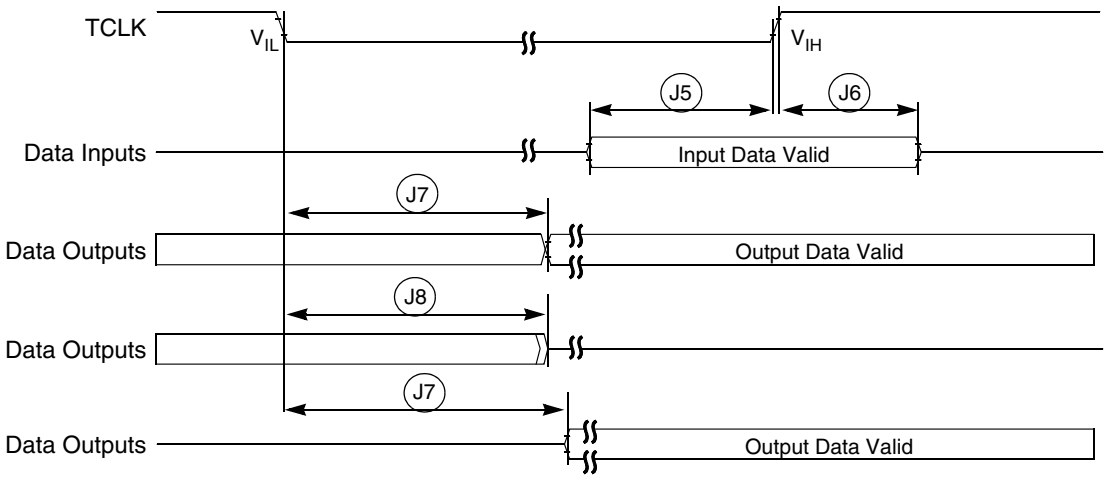

Figure 17. Boundary Scan (JTAG) Timing

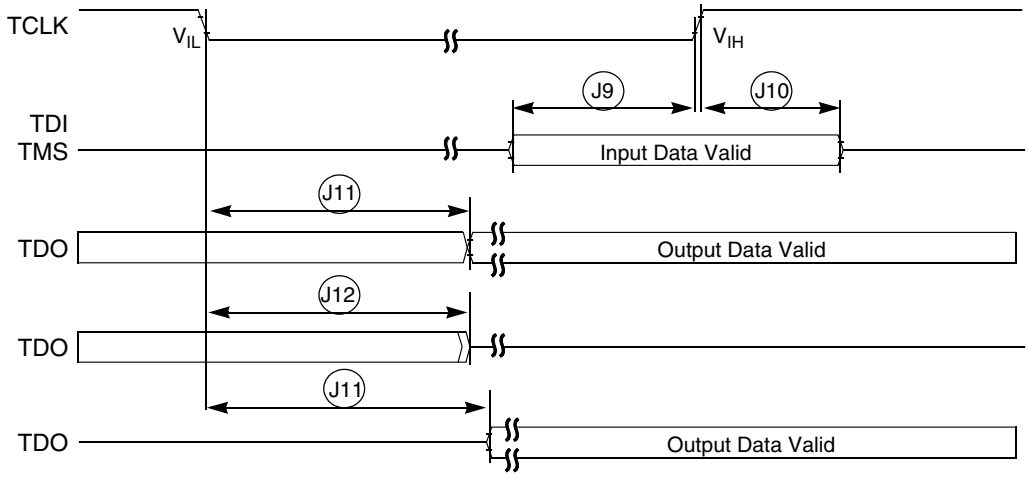

Figure 18. Test Access Port Timing

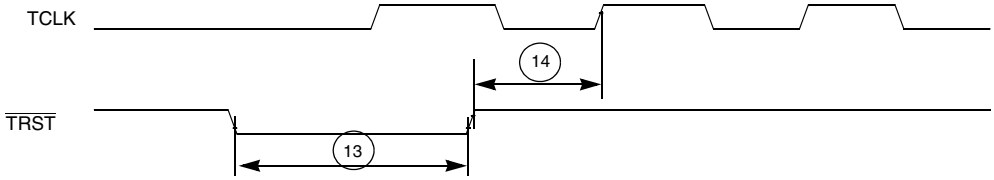

Figure 19. $\overline{TRST}$ Timing

Figure 21 shows BDM serial port AC timing for the values in Table 29.

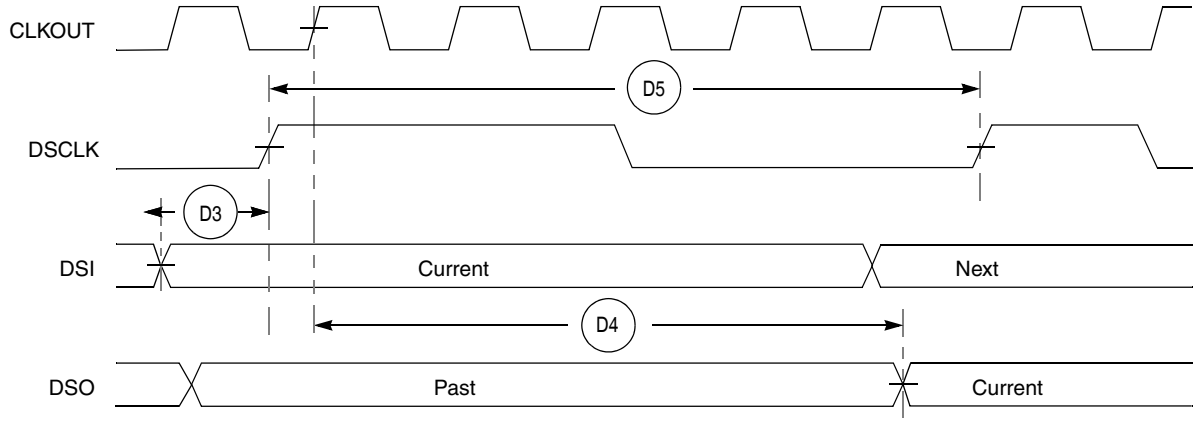

Figure 21. BDM Serial Port AC Timing

3 Package Information

The latest package outline drawings are available on the product summary pages on http://www.freescale.com/coldfire. Table 30 lists the case outline numbers per device. Use these numbers in the web page's keyword search engine to find the latest package outline drawings.

Table 30. Package Information

Device	Package Type	Case Outline Numbers
MCF52252	100 LQFP	98ASS23308W
MCF52254		
MCF52255		
MCF52256	144 LQFP or 144 MAPBGA	98ASS23177W 98ASH70694A
MCF52258		
MCF52259		